

08-09-02

AF/2800

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Ono et al. Examiner: J. Mitchell
Serial No.: 09/842487 Group Art Unit: 2822
Filed: April 25, 2001 Docket: 10873.0447USD1
Confirmation No.: 7930 Notice of Allow. N/A
Due Date: August 7, 2002 Date:
Title: EDGE TESTING ELECTRODE FOR A SEMICONDUCTOR DEVICE

CERTIFICATE UNDER 37 CFR 1.10:

"Express Mail" mailing label number: EV143559713US
Date of Deposit: August 7, 2002

I hereby certify that this paper or fee is being deposited with the U.S. Postal Service "Express Mail Post Office to Addressee" service under 37 CFR 1.10 on the date indicated above and is addressed to Commissioner for Patents and Trademarks, Box AF, Washington, D.C. 20231.

By: *John Junkers*
Name: John Junkers

Box AF
Commissioner for Patents
Washington, D.C. 20231

Sir:

We are transmitting herewith the attached:

- Return postcard
- Transmittal Sheet in duplicate containing Certificate of Mailing
- Amendment Including Version With Markings To Show Changes Made

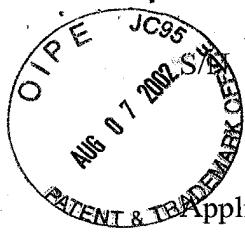
Please consider this a PETITION FOR EXTENSION OF TIME for a sufficient number of months to enter these papers or any future reply, if appropriate. Please charge any additional fees or credit overpayment to Deposit Account No. 13-2725. A duplicate of this sheet is enclosed.

3200 IDS Center
80 South Eighth Street
Minneapolis, Minnesota 55402-2215
USA
(612) 332-5300

By: *Douglas P. Mueller*
Name: Douglas P. Mueller
Reg. No.: 30,300
DPM:MLL/tlp



RECEIVED
TECHNOLOGY CENTER 2800
AUG 13 2002



09/842,487

PATENT

*H. Harada
OES
Robert
3/16/02*

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: ONO ET AL Examiner: J. MITCHELL
Serial No.: 09/842,487 Group Art Unit: 2822
Filed: APRIL 25, 2001 Docket No.: 10873.447USDA
Title: EDGE TESTING ELECTRODE FOR A SEMICONDUCTOR DEVICE
(PREVIOUSLY: "SEMICONDUCTOR DEVICE")

CERTIFICATE UNDER 37 CFR 1.10:

"Express Mail" mailing label number: EV143559713US
Date of Deposit: August 7, 2002

I hereby certify that this correspondence is being deposited with the United States Postal Service "Express Mail Post Office to Addressee" service under 37 CFR 1.10 on the date indicated above and is addressed to Commissioner for Patents, Washington, D.C. 20231.

By: *[Signature]*
Name: John Junkens

TECHNOLOGY CENTER 2800
AUG 13 2002

RECEIVED

BOX AF
Commissioner for Patents
Washington, D.C. 20231

Dear Sir:

In response to the final Office Action mailed May 7, 2002, Applicants provide the following amendments and remarks.

In the Specification

Please amend the title to read as follows:

EDGE TESTING ELECTRODE FOR A SEMICONDUCTOR DEVICE

In the Claims

Please cancel claim 24 without prejudice or disclaimer to the subject matter.

Please amend claim 22 to read as follows.

22. (twice amended) A semiconductor device manufactured by a wire bonding method using a metal wire, comprising a dedicated inspection region adapted to be contacted by a probe needle for inspection brought into contact therewith, and a region in which a metal ball formed at a tip of said metal wire by electric discharge is bonded to a terminal electrode formed on the semiconductor device, wherein a shape of the terminal electrode is rectangular, the shape having a portion protruded from a square that surrounds the region wherein the metal ball is bonded to the terminal electrode, the protruded portion being the dedicated inspection region adapted to be contacted by the probe needle.

